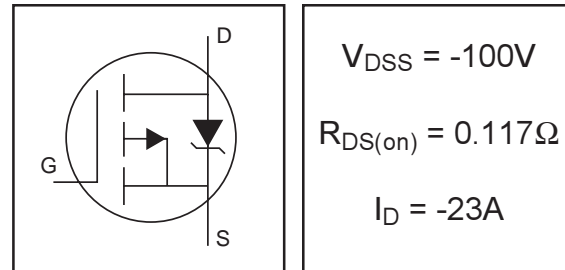


# IRFP9140NPbF

HEXFET® Power MOSFET

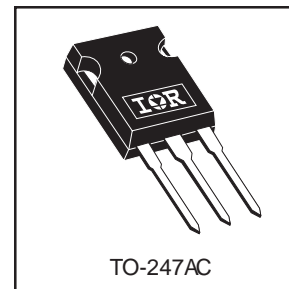
- Advanced Process Technology
- Dynamic dv/dt Rating
- 175°C Operating Temperature
- P-Channel
- Fast Switching
- Fully Avalanche Rated
- Lead-Free



## Description

Fifth Generation HEXFETs from International Rectifier utilize advanced processing techniques to achieve extremely low on-resistance per silicon area. This benefit, combined with the fast switching speed and ruggedized device design that HEXFET Power MOSFETs are well known for, provides the designer with an extremely efficient and reliable device for use in a wide variety of applications.

The TO-247 package is preferred for commercial-industrial applications where higher power levels preclude the use of TO-220 devices. The TO-247 is similar but superior to the earlier TO-218 package because of its isolated mounting hole.



## Absolute Maximum Ratings

	Parameter	Max.	Units
$I_D @ T_C = 25^\circ\text{C}$	Continuous Drain Current, $V_{GS} @ -10\text{V}$	-23	A
$I_D @ T_C = 100^\circ\text{C}$	Continuous Drain Current, $V_{GS} @ -10\text{V}$	-16	
$I_{DM}$	Pulsed Drain Current ①⑤	-76	
$P_D @ T_C = 25^\circ\text{C}$	Power Dissipation	140	W
	Linear Derating Factor	0.91	W/°C
$V_{GS}$	Gate-to-Source Voltage	$\pm 20$	V
$E_{AS}$	Single Pulse Avalanche Energy②⑤	430	mJ
$I_{AR}$	Avalanche Current①	-11	A
$E_{AR}$	Repetitive Avalanche Energy①	14	mJ
dv/dt	Peak Diode Recovery dv/dt ③⑤	-5.0	V/ns
$T_J$	Operating Junction and	-55 to + 175	°C
$T_{STG}$	Storage Temperature Range		
	Soldering Temperature, for 10 seconds	300 (1.6mm from case )	
	Mounting torque, 6-32 or M3 screw	10 lbf•in (1.1N•m)	

## Thermal Resistance

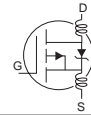
	Parameter	Typ.	Max.	Units
$R_{\theta JC}$	Junction-to-Case	---	1.1	°C/W
$R_{\theta CS}$	Case-to-Sink, Flat, Greased Surface	0.24	---	
$R_{\theta JA}$	Junction-to-Ambient	---	40	

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International  
IR Rectifier

## Electrical Characteristics @ T<sub>J</sub> = 25°C (unless otherwise specified)

	Parameter	Min.	Typ.	Max.	Units	Conditions
V <sub>(BR)DSS</sub>	Drain-to-Source Breakdown Voltage	-100	—	—	V	V <sub>GS</sub> = 0V, I <sub>D</sub> = -250μA
ΔV <sub>(BR)DSS/ΔT<sub>J</sub></sub>	Breakdown Voltage Temp. Coefficient	—	-0.11	—	V/°C	Reference to 25°C, I <sub>D</sub> = -1mA <sup>⑤</sup>
R <sub>DS(on)</sub>	Static Drain-to-Source On-Resistance	—	—	0.117	Ω	V <sub>GS</sub> = -10V, I <sub>D</sub> = -13A <sup>④</sup>
V <sub>GS(th)</sub>	Gate Threshold Voltage	-2.0	—	-4.0	V	V <sub>DS</sub> = V <sub>GS</sub> , I <sub>D</sub> = -250μA
g <sub>fs</sub>	Forward Transconductance	5.3	—	—	S	V <sub>DS</sub> = -50V, I <sub>D</sub> = 11A <sup>⑤</sup>
I <sub>DSS</sub>	Drain-to-Source Leakage Current	—	—	-25	μA	V <sub>DS</sub> = -100V, V <sub>GS</sub> = 0V
		—	—	-250		V <sub>DS</sub> = -80V, V <sub>GS</sub> = 0V, T <sub>J</sub> = 150°C
I <sub>GSS</sub>	Gate-to-Source Forward Leakage	—	—	100	nA	V <sub>GS</sub> = 20V
	Gate-to-Source Reverse Leakage	—	—	-100		V <sub>GS</sub> = -20V
Q <sub>g</sub>	Total Gate Charge	—	—	97	nC	I <sub>D</sub> = -11A
Q <sub>gs</sub>	Gate-to-Source Charge	—	—	15		V <sub>DS</sub> = -80V
Q <sub>gd</sub>	Gate-to-Drain ("Miller") Charge	—	—	51		V <sub>GS</sub> = -10V, See Fig. 6 and 13 <sup>④⑤</sup>
t <sub>d(on)</sub>	Turn-On Delay Time	—	15	—	ns	V <sub>DD</sub> = -50V I <sub>D</sub> = -11A R <sub>G</sub> = 5.1Ω R <sub>D</sub> = 4.2Ω, See Fig. 10 <sup>④⑤</sup>
t <sub>r</sub>	Rise Time	—	67	—		
t <sub>d(off)</sub>	Turn-Off Delay Time	—	51	—		
t <sub>f</sub>	Fall Time	—	51	—		
L <sub>D</sub>	Internal Drain Inductance	—	5.0	—	nH	Between lead, 6mm (0.25in.) from package and center of die contact
L <sub>S</sub>	Internal Source Inductance	—	13	—		
C <sub>ISS</sub>	Input Capacitance	—	1300	—	pF	V <sub>GS</sub> = 0V V <sub>DS</sub> = -25V f = 1.0MHz, See Fig. 5 <sup>⑤</sup>
C <sub>OSS</sub>	Output Capacitance	—	400	—		
C <sub>RSS</sub>	Reverse Transfer Capacitance	—	240	—		



## Source-Drain Ratings and Characteristics

	Parameter	Min.	Typ.	Max.	Units	Conditions
I <sub>S</sub>	Continuous Source Current (Body Diode)	—	—	-23	A	MOSFET symbol showing the integral reverse p-n junction diode.
I <sub>SM</sub>	Pulsed Source Current (Body Diode) <sup>①⑤</sup>	—	—	-76		
V <sub>SD</sub>	Diode Forward Voltage	—	—	-1.3	V	T <sub>J</sub> = 25°C, I <sub>S</sub> = -13A, V <sub>GS</sub> = 0V <sup>④</sup>
t <sub>rr</sub>	Reverse Recovery Time	—	150	220	ns	T <sub>J</sub> = 25°C, I <sub>F</sub> = -11A
Q <sub>rr</sub>	Reverse Recovery Charge	—	830	1200	μC	di/dt = -100A/μs <sup>④</sup>
t <sub>on</sub>	Forward Turn-On Time	Intrinsic turn-on time is negligible (turn-on is dominated by L <sub>S</sub> +L <sub>D</sub> )				

### Notes:

① Repetitive rating; pulse width limited by max. junction temperature. ( See fig. 11 )

② Starting T<sub>J</sub> = 25°C, L = 7.1mH  
R<sub>G</sub> = 25Ω, I<sub>AS</sub> = -11A. (See Figure 12)

③ I<sub>SD</sub> ≤ -11A, di/dt ≤ -470A/μs, V<sub>DD</sub> ≤ V<sub>(BR)DSS</sub>,  
T<sub>J</sub> ≤ 175°C

④ Pulse width ≤ 300μs; duty cycle ≤ 2%.

⑤ Uses IRF9540N data and test conditions

